


<b>Search Notes</b>  	<b>Application/Control No.</b>  10574920	<b>Applicant(s)/Patent Under Reexamination</b>  MIYAZAWA ET AL.
	<b>Examiner</b>  YUN QIAN	<b>Art Unit</b>  4162

SEARCHED			
Class	Subclass	Date	Examiner
423	445	5/31/2009	yq

SEARCH NOTES		
Search Notes	Date	Examiner
STN and EAST search (PG Pub, USPAT, EPO, JPO, inventor search, consult with Curtis Mayes, 423/text search	9/8/2008	yq
updated search	5/31/2009	yq
Updated search	2/9/2010	yq

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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